

N-Channel and P-Channel 40V(D-S) MOSFET

Product summary			
V_{DS}	40	-40	V
$R_{DS(ON)}$ (at $V_{GS}=10V$) Typ.	9.9	19.2	m Ω
$R_{DS(ON)}$ (at $V_{GS}=4.5V$) Typ.	13.5	24.2	m Ω
I_D ($T_C=25^\circ C$)	34	-24	A

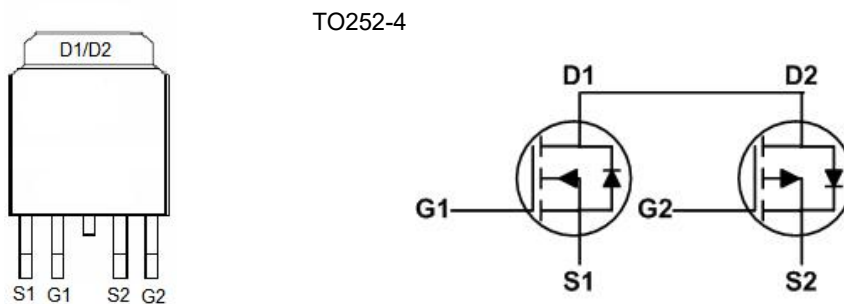
Features

- Low Gate Charge
- Advanced Trench Technology

Applications

- Power management functions
- PWM Application
- Load switch

Pin Configuration



Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECFD30C04	TO252-4	13"	2500pcs

Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	N-Rating	P-Rating	Units	
V_{DS}	Drain-Source Voltage	40	-40	V	
V_{GS}	Gate-Source Voltage	± 20	± 20	V	
I_D	Continuous Drain Current	$T_C=25^\circ C$	34	-24	A
		$T_C=100^\circ C$	21.5	-15.2	A
I_{DM}	Pulse Drain Current Tested ^A	134	-95	A	
E_{AS}	Single Pulse Avalanche Energy ^B	33	42	mJ	
P_D	Power Dissipation	$T_C=25^\circ C$	25	25	W
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	-55 to +150	$^\circ C$	

Thermal Characteristics

Symbol	Parameter	Typical	Units
$R_{\theta JC}$	Thermal Resistance Junction-Case	5	$^\circ C/W$

N-Channel Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=40V, V_{GS}=0V$	--	--	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	--	--	± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.5	2.2	V
$R_{DS(on)}$	Drain-Source On-State Resistance ^C	$V_{GS}=10V, I_D=10A$	--	9.9	12.6	m Ω
		$V_{GS}=4.5V, I_D=5A$	--	13.5	17	m Ω
V_{SD}	Diode Forward Voltage	$I_S=10A, V_{GS}=0V$	--	--	1.2	V
I_S	Maximum Body-Diode Continuous Current		--	--	34	A
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=20V$ $f=1\text{MHz}$	--	1210	--	pF
C_{oss}	Output Capacitance		--	85	--	pF
C_{riss}	Reverse Transfer Capacitance		--	56	--	pF
Q_g	Total Gate Charge	$V_{DS}=20V, I_D=10A$ $V_{GS}=0 \text{ to } 10V$	--	27	--	nC
Q_{gs}	Gate-Source Charge		--	8	--	nC
Q_{gd}	Gate-Drain Charge		--	6	--	nC
$t_{D(on)}$	Turn-on Delay Time	$V_{DD}=20V$ $I_D=10A, R_{GEN}=3\Omega,$ $V_{GS}=10V$	--	7.8	--	ns
t_r	Turn-on Rise Time		--	12.3	--	ns
$t_{D(off)}$	Turn-off Delay Time		--	27.5	--	ns
t_f	Turn-off Fall Time		--	6.9	--	ns
t_{rr}	Reverse Recovery Time	$I_F=10A$ $di/dt=100A/\mu s$	--	11	--	ns
Q_{rr}	Reverse Recovery Charge		--	7	--	nC

A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. The E_{AS} data shows Max. rating . The test condition is $T_J=25^\circ\text{C}, V_{DD}=20V, R_G=25\text{ohm}, V_G=10V, L=0.5\text{mH}, I_{AS}=11.5A$.

C. Pulse Test: Pulse Width $\leq 300\mu s$, Duty cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

P-Channel Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-40	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-40V, V_{GS}=0V$	--	--	-1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	--	--	± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.0	-1.7	-2.5	V
$R_{DS(ON)}$	Drain-Source On-State Resistance ^C	$V_{GS}=-10V, I_D=-5A$	--	19.2	25	m Ω
		$V_{GS}=-4.5V, I_D=-4A$	--	24.2	31.5	m Ω
V_{SD}	Diode Forward Voltage	$I_S=-1A, V_{GS}=0V$	--	--	-1.0	V
I_S	Maximum Body-Diode Continuous Current		--	--	-24	A
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=-20V$ $f=1\text{MHz}$	--	1436	--	pF
C_{oss}	Output Capacitance		--	122	--	pF
C_{riss}	Reverse Transfer Capacitance		--	85	--	pF
Q_g	Total Gate Charge	$V_{DS}=-20V, I_D=-10A$ $V_{GS}=0$ to $-10V$	--	28	--	nC
Q_{gs}	Gate-Source Charge		--	7	--	nC
Q_{gd}	Gate-Drain Charge		--	5.5	--	nC
$t_{D(on)}$	Turn-on Delay Time	$V_{DD}=-20V$ $I_D=-10A, R_{GEN}=3\Omega,$ $V_{GS}=-10V$	--	7.8	--	ns
t_r	Turn-on Rise Time		--	29	--	ns
$t_{D(off)}$	Turn-off Delay Time		--	36	--	ns
t_f	Turn-off Fall Time		--	47	--	ns
t_{rr}	Reverse Recovery Time	$I_F=-10A$ $di/dt=100A/\mu s$	--	14	--	ns
Q_{rr}	Reverse Recovery Charge		--	7	--	nC

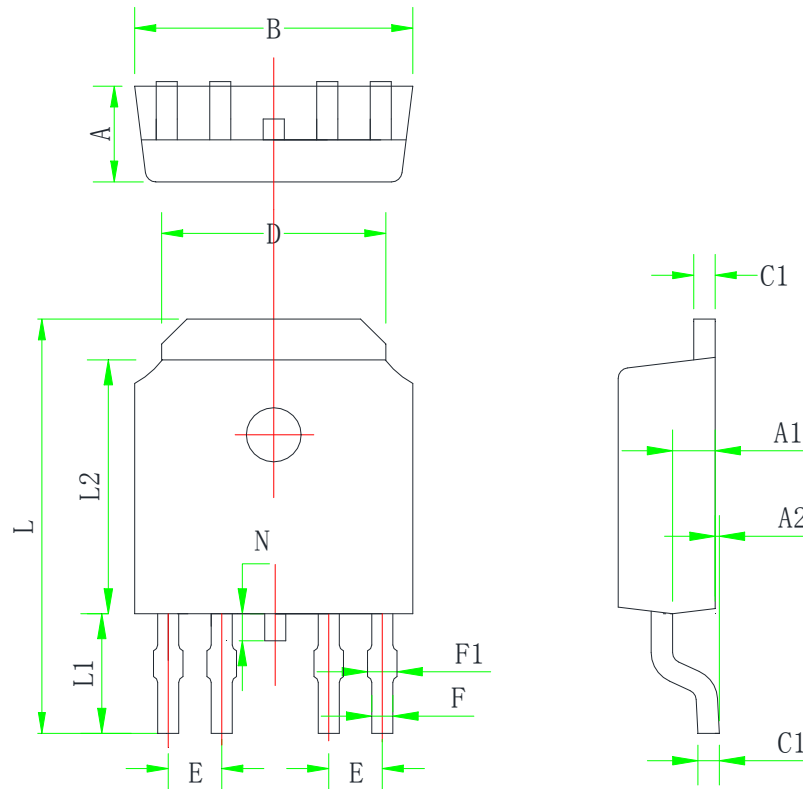
A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. The E_{AS} data shows Max. rating . The test condition is $T_J=25^\circ\text{C}, V_{DD}=-20V, R_G=25\text{ohm}, V_G=-10V, L=0.5\text{mH}, I_{AS}=-13A$.

C. Pulse Test: Pulse Width $\leq 300\mu s$, Duty cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

TO252-4L Package Information



Symbol	Min	Typ	Max
A	2.20	2.30	2.40
A1	0.91	1.01	1.11
A2	0.05	0.15	0.25
B	6.45	6.60	6.75
C	0.45	0.50	0.58
C1	0.45	0.50	0.58
D	5.12	5.32	5.52
E	1.27 TYP		
F	0.45	0.60	0.75
F1	0.40	0.50	0.60
L	9.70	10.00	10.20
L1	2.6	2.8	3.0
L2	5.95	6.10	6.25
N	0.45	0.65	0.85